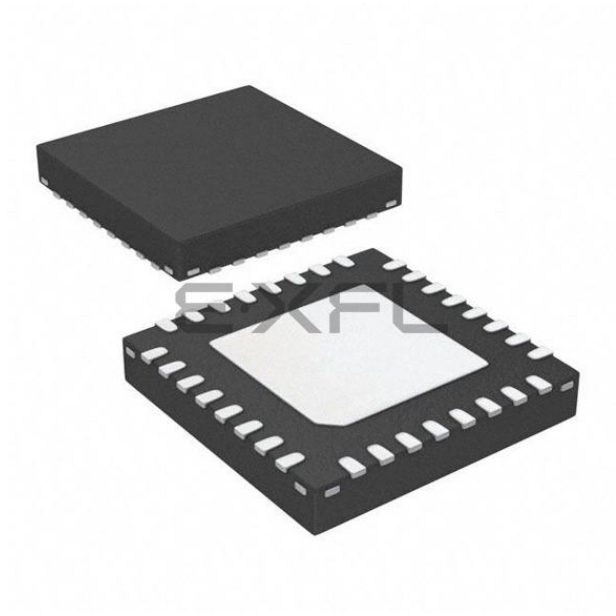


Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Discontinued at Digi-Key
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	50MHz
Connectivity	I²C, Microwire, SmartCard, SPI, SSP, UART/USART, USB
Peripherals	Brown-out Detect/Reset, POR, WDT
Number of I/O	26
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	6K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-VQFN Exposed Pad
Supplier Device Package	32-HVQFN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/lpc11u12fhn33-201

6.2 Pin description

Table 3 shows all pins and their assigned digital or analog functions ordered by GPIO port number. The default function after reset is listed first. All port pins have internal pull-up resistors enabled after reset with the exception of the true open-drain pins PIO0_4 and PIO0_5.

Every port pin has a corresponding IOCON register for programming the digital or analog function, the pull-up/pull-down configuration, the repeater, and the open-drain modes.

The USART, counter/timer, and SSP functions are available on more than one port pin. Table 4 shows how peripheral functions are assigned to port pins.

Table 3. Pin description

Symbol	Pin HVQFN33	Pin LQFP48	Ball TFBGA48	Reset state [1]	Type	Description
$\overline{\text{RESET}}$/PIO0_0	2	3	C1 [2]	I; PU	I	**$\overline{\text{RESET}}$ —** External reset input with 20 ns glitch filter. A LOW-going pulse as short as 50 ns on this pin resets the device, causing I/O ports and peripherals to take on their default states, and processor execution to begin at address 0. This pin also serves as the debug select input. LOW level selects the JTAG boundary scan. HIGH level selects the ARM SWD debug mode. In deep power-down mode, this pin must be pulled HIGH externally. The $\overline{\text{RESET}}$ pin can be left unconnected or be used as a GPIO pin if an external $\overline{\text{RESET}}$ function is not needed and Deep power-down mode is not used.
				-	I/O	**PIO0_0 —** General purpose digital input/output pin.
PIO0_1/CLKOUT/ CT32B0_MAT2/ USB_FTOGGLE	3	4	C2 [3][4]	I; PU	I/O	**PIO0_1 —** General purpose digital input/output pin. A LOW level on this pin during reset starts the ISP command handler.
				-	O	**CLKOUT —** Clockout pin.
				-	O	**CT32B0_MAT2 —** Match output 2 for 32-bit timer 0.
				-	O	**USB_FTOGGLE —** USB 1 ms Start-of-Frame signal.
PIO0_2/SSEL0/ CT16B0_CAP0	8	10	F1 [3]	I; PU	I/O	**PIO0_2 —** General purpose digital input/output pin.
				-	I/O	**SSEL0 —** Slave select for SSP0.
				-	I	**CT16B0_CAP0 —** Capture input 0 for 16-bit timer 0.
PIO0_3/USB_VBUS	9	14	H2 [3]	I; PU	I/O	**PIO0_3 —** General purpose digital input/output pin.
				-	I	**USB_VBUS —** Monitors the presence of USB bus power.

Table 3. Pin description *…continued*

Symbol	Pin HVQFN33	Pin LQFP48	Ball TFBGA48	Reset state [1]	Type	Description
TMS/PIO0_12/AD1/ CT32B1_CAP0	22	33	C7 [7]	I; PU	I	**TMS —** Test Mode Select for JTAG interface.
				-	I/O	**PIO_12 —** General purpose digital input/output pin.
				-	I	**AD1 —** A/D converter, input 1.
				-	I	**CT32B1_CAP0 —** Capture input 0 for 32-bit timer 1.
TDO/PIO0_13/AD2/ CT32B1_MAT0	23	34	C8 [7]	I; PU	O	**TDO —** Test Data Out for JTAG interface.
				-	I/O	**PIO0_13 —** General purpose digital input/output pin.
				-	I	**AD2 —** A/D converter, input 2.
				-	O	**CT32B1_MAT0 —** Match output 0 for 32-bit timer 1.
$\overline{\text{TRST}}$/PIO0_14/AD3/ CT32B1_MAT1	24	35	B7 [7]	I; PU	I	**$\overline{\text{TRST}}$ —** Test Reset for JTAG interface.
				-	I/O	**PIO0_14 —** General purpose digital input/output pin.
				-	I	**AD3 —** A/D converter, input 3.
				-	O	**CT32B1_MAT1 —** Match output 1 for 32-bit timer 1.
SWDIO/PIO0_15/AD4/ CT32B1_MAT2	25	39	B6 [7]	I; PU	I/O	**SWDIO —** Serial wire debug input/output.
				-	I/O	**PIO0_15 —** General purpose digital input/output pin.
				-	I	**AD4 —** A/D converter, input 4.
				-	O	**CT32B1_MAT2 —** Match output 2 for 32-bit timer 1.
PIO0_16/AD5/ CT32B1_MAT3/WAKEUP	26	40	A6 [7]	I; PU	I/O	**PIO0_16 —** General purpose digital input/output pin.
				-	I	**AD5 —** A/D converter, input 5.
				-	O	**CT32B1_MAT3 —** Match output 3 for 32-bit timer 1.
				-	I	**WAKEUP —** Deep power-down mode wake-up pin with 20 ns glitch filter. This pin must be pulled HIGH externally to enter Deep power-down mode and pulled LOW to exit Deep power-down mode. A LOW-going pulse as short as 50 ns wakes up the part.
PIO0_17/$\overline{\text{RTS}}$/ CT32B0_CAP0/SCLK	30	45	A3 [3]	I; PU	I/O	**PIO0_17 —** General purpose digital input/output pin.
				-	O	**$\overline{\text{RTS}}$ —** Request To Send output for USART.
				-	I	**CT32B0_CAP0 —** Capture input 0 for 32-bit timer 0.
				-	I/O	**SCLK —** Serial clock input/output for USART in synchronous mode.

Table 3. Pin description *…continued*

Symbol	Pin HVQFN33	Pin LQFP48	Ball TFBGA48		Reset state [1]	Type	Description
PIO1_14/$\overline{\text{DSR}}$/ CT16B0_MAT1/RXD	-	37	A8	[3]	I; PU	I/O	**PIO1_14 —** General purpose digital input/output pin.
					-	I	**$\overline{\text{DSR}}$ —** Data Set Ready input for USART.
					-	O	**CT16B0_MAT1 —** Match output 1 for 16-bit timer 0.
					-	I	**RXD —** Receiver input for USART.
PIO1_15/$\overline{\text{DCD}}$/ CT16B0_MAT2/SCK1	28	43	A4	[3]	I; PU	I/O	**PIO1_15 —** General purpose digital input/output pin.
						I	**$\overline{\text{DCD}}$ —** Data Carrier Detect input for USART.
					-	O	**CT16B0_MAT2 —** Match output 2 for 16-bit timer 0.
					-	I/O	**SCK1 —** Serial clock for SSP1.
PIO1_16/$\overline{\text{RI}}$/ CT16B0_CAP0	-	48	A2	[3]	I; PU	I/O	**PIO1_16 —** General purpose digital input/output pin.
					-	I	**$\overline{\text{RI}}$ —** Ring Indicator input for USART.
					-	I	**CT16B0_CAP0 —** Capture input 0 for 16-bit timer 0.
PIO1_19/$\overline{\text{DTR}}$/SSEL1	1	2	B1	[3]	I; PU	I/O	**PIO1_19 —** General purpose digital input/output pin.
					-	O	**$\overline{\text{DTR}}$ —** Data Terminal Ready output for USART.
					-	I/O	**SSEL1 —** Slave select for SSP1.
PIO1_20/$\overline{\text{DSR}}$/SCK1	-	13	H1	[3]	I; PU	I/O	**PIO1_20 —** General purpose digital input/output pin.
					-	I	**$\overline{\text{DSR}}$ —** Data Set Ready input for USART.
					-	I/O	**SCK1 —** Serial clock for SSP1.
PIO1_21/$\overline{\text{DCD}}$/MISO1	-	26	G8	[3]	I; PU	I/O	**PIO1_21 —** General purpose digital input/output pin.
					-	I	**$\overline{\text{DCD}}$ —** Data Carrier Detect input for USART.
					-	I/O	**MISO1 —** Master In Slave Out for SSP1.
PIO1_22/$\overline{\text{RI}}$/MOSI1	-	38	A7	[3]	I; PU	I/O	**PIO1_22 —** General purpose digital input/output pin.
					-	I	**$\overline{\text{RI}}$ —** Ring Indicator input for USART.
					-	I/O	**MOSI1 —** Master Out Slave In for SSP1.
PIO1_23/CT16B1_MAT1/ SSEL1	-	18	H4	[3]	I; PU	I/O	**PIO1_23 —** General purpose digital input/output pin.
					-	O	**CT16B1_MAT1 —** Match output 1 for 16-bit timer 1.
					-	I/O	**SSEL1 —** Slave select for SSP1.

Table 3. Pin description *…continued*

Symbol	Pin HVQFN33	Pin LQFP48	Ball TFBGA48	Reset state [1]	Type	Description
PIO1_24/CT32B0_MAT0	-	21	G6 [3]	I; PU	I/O	**PIO1_24 —** General purpose digital input/output pin.
				-	O	**CT32B0_MAT0 —** Match output 0 for 32-bit timer 0.
PIO1_25/CT32B0_MAT1	-	1	A1 [3]	I; PU	I/O	**PIO1_25 —** General purpose digital input/output pin.
				-	O	**CT32B0_MAT1 —** Match output 1 for 32-bit timer 0.
PIO1_26/CT32B0_MAT2/ RXD	-	11	G2 [3]	I; PU	I/O	**PIO1_26 —** General purpose digital input/output pin.
				-	O	**CT32B0_MAT2 —** Match output 2 for 32-bit timer 0.
				-	I	**RXD —** Receiver input for USART.
PIO1_27/CT32B0_MAT3/ TXD	-	12	G1 [3]	I; PU	I/O	**PIO1_27 —** General purpose digital input/output pin.
				-	O	**CT32B0_MAT3 —** Match output 3 for 32-bit timer 0.
				-	O	**TXD —** Transmitter output for USART.
PIO1_28/CT32B0_CAP0/ SCLK	-	24	H7 [3]	I; PU	I/O	**PIO1_28 —** General purpose digital input/output pin.
				-	I	**CT32B0_CAP0 —** Capture input 0 for 32-bit timer 0.
				-	I/O	**SCLK —** Serial clock input/output for USART in synchronous mode.
PIO1_29/SCK0/ CT32B0_CAP1	-	31	D7 [3]	I; PU	I/O	**PIO1_29 —** General purpose digital input/output pin.
				-	I/O	**SCK0 —** Serial clock for SSP0.
				-	I	**CT32B0_CAP1 —** Capture input 1 for 32-bit timer 0.
PIO1_31	-	25	- [3]	I; PU	I/O	**PIO1_31 —** General purpose digital input/output pin.
USB_DM	13	19	G5 [8]	F	-	**USB_DM —** USB bidirectional D− line.
USB_DP	14	20	H5 [8]	F	-	**USB_DP —** USB bidirectional D+ line.
XTALIN	4	6	D1 [9]	-	-	Input to the oscillator circuit and internal clock generator circuits. Input voltage must not exceed 1.8 V.
XTALOUT	5	7	E1 [9]	-	-	Output from the oscillator amplifier.
V_{DD}	6; 29	8; 44	B4, E2	-	-	Supply voltage to the internal regulator, the external rail, and the ADC. Also used as the ADC reference voltage.
V_{SS}	33	5; 41	B5, D2	-	-	Ground.

7. Functional description

7.1 On-chip flash programming memory

The LPC11U1x contain up to 32 kB on-chip flash program memory. The flash can be programmed using In-System Programming (ISP) or In-Application Programming (IAP) via the on-chip boot loader software.

7.2 SRAM

The LPC11U1x contain a total of 6 kB on-chip static RAM memory.

7.3 On-chip ROM

The on-chip ROM contains the boot loader and the following Application Programming Interfaces (APIs):

- In-System Programming (ISP) and In-Application Programming (IAP) support for flash programming
- Power profiles for configuring power consumption and PLL settings
- 32-bit integer division routines

7.4 Memory map

The LPC11U1x incorporates several distinct memory regions, shown in the following figures. Figure 5 shows the overall map of the entire address space from the user program viewpoint following reset. The interrupt vector area supports address remapping.

The AHB peripheral area is 2 MB in size and is divided to allow for up to 128 peripherals. The APB peripheral area is 512 kB in size and is divided to allow for up to 32 peripherals. Each peripheral of either type is allocated 16 kB of space. This allows simplifying the address decoding for each peripheral.

on-chip peripherals, allowing fine tuning of power consumption by eliminating all dynamic power use in any peripherals that are not required for the application. Selected peripherals have their own clock divider which provides even better power control.

7.16.5.1 Power profiles

The power consumption in Active and Sleep modes can be optimized for the application through simple calls to the power profile. The power configuration routine configures the LPC11U1x for one of the following power modes:

- Default mode corresponding to power configuration after reset.
- CPU performance mode corresponding to optimized processing capability.
- Efficiency mode corresponding to optimized balance of current consumption and CPU performance.
- Low-current mode corresponding to lowest power consumption.

In addition, the power profile includes routines to select the optimal PLL settings for a given system clock and PLL input clock.

Remark: When using the USB, configure the LPC11U1x in Default mode.

7.16.5.2 Sleep mode

When Sleep mode is entered, the clock to the core is stopped. Resumption from the Sleep mode does not need any special sequence but re-enabling the clock to the ARM core.

In Sleep mode, execution of instructions is suspended until either a reset or interrupt occurs. Peripheral functions continue operation during Sleep mode and may generate interrupts to cause the processor to resume execution. Sleep mode eliminates dynamic power used by the processor itself, memory systems and related controllers, and internal buses.

7.16.5.3 Deep-sleep mode

In Deep-sleep mode, the LPC11U1x is in Sleep-mode and all peripheral clocks and all clock sources are off with the exception of the IRC. The IRC output is disabled unless the IRC is selected as input to the watchdog timer. In addition all analog blocks are shut down and the flash is in stand-by mode. In Deep-sleep mode, the user has the option to keep the watchdog oscillator and the BOD circuit running for self-timed wake-up and BOD protection.

The LPC11U1x can wake up from Deep-sleep mode via reset, selected GPIO pins, a watchdog timer interrupt, or an interrupt generating USB port activity.

Deep-sleep mode saves power and allows for short wake-up times.

7.16.5.4 Power-down mode

In Power-down mode, the LPC11U1x is in Sleep-mode and all peripheral clocks and all clock sources are off with the exception of watchdog oscillator if selected. In addition all analog blocks and the flash are shut down. In Power-down mode, the user has the option to keep the BOD circuit running for BOD protection.

The LPC11U1x can wake up from Power-down mode via reset, selected GPIO pins, a watchdog timer interrupt, or an interrupt generating USB port activity.

Power-down mode reduces power consumption compared to Deep-sleep mode at the expense of longer wake-up times.

7.16.5.5 Deep power-down mode

In Deep power-down mode, power is shut off to the entire chip with the exception of the WAKEUP pin. The LPC11U1x can wake up from Deep power-down mode via the WAKEUP pin.

The LPC11U1x can be prevented from entering Deep power-down mode by setting a lock bit in the PMU block. Locking out Deep power-down mode enables the user to always keep the watchdog timer or the BOD running.

When entering Deep power-down mode, an external pull-up resistor is required on the WAKEUP pin to hold it HIGH. The $\overline{\text{RESET}}$ pin must also be held HIGH to prevent it from floating while in Deep power-down mode.

7.16.6 System control

7.16.6.1 Reset

Reset has four sources on the LPC11U1x: the $\overline{\text{RESET}}$ pin, the Watchdog reset, power-on reset (POR), and the BrownOut Detection (BOD) circuit. The $\overline{\text{RESET}}$ pin is a Schmitt trigger input pin. Assertion of chip reset by any source, once the operating voltage attains a usable level, starts the IRC and initializes the flash controller.

A LOW-going pulse as short as 50 ns resets the part.

When the internal Reset is removed, the processor begins executing at address 0, which is initially the Reset vector mapped from the boot block. At that point, all of the processor and peripheral registers have been initialized to predetermined values.

An external pull-up resistor is required on the $\overline{\text{RESET}}$ pin if Deep power-down mode is used.

7.16.6.2 Brownout detection

The LPC11U1x includes four levels for monitoring the voltage on the V_{DD} pin. If this voltage falls below one of the four selected levels, the BOD asserts an interrupt signal to the NVIC. This signal can be enabled for interrupt in the Interrupt Enable Register in the NVIC in order to cause a CPU interrupt; if not, software can monitor the signal by reading a dedicated status register. Four additional threshold levels can be selected to cause a forced reset of the chip.

7.16.6.3 Code security (Code Read Protection - CRP)

This feature of the LPC11U1x allows user to enable different levels of security in the system so that access to the on-chip flash and use of the Serial Wire Debugger (SWD) and In-System Programming (ISP) can be restricted. When needed, CRP is invoked by programming a specific pattern into a dedicated flash location. IAP commands are not affected by the CRP.

In addition, ISP entry via the PIO0_1 pin can be disabled without enabling CRP. For details see the LPC11U1x *user manual*.

There are three levels of Code Read Protection:

7.17 Emulation and debugging

Debug functions are integrated into the ARM Cortex-M0. Serial wire debug functions are supported in addition to a standard JTAG boundary scan. The ARM Cortex-M0 is configured to support up to four breakpoints and two watch points.

The $\overline{\text{RESET}}$ pin selects between the JTAG boundary scan ($\overline{\text{RESET}}$ = LOW) and the ARM SWD debug ($\overline{\text{RESET}}$ = HIGH). The ARM SWD debug port is disabled while the LPC11U1x is in reset.

To perform boundary scan testing, follow these steps:

1. Erase any user code residing in flash.
2. Power up the part with the $\overline{\text{RESET}}$ pin pulled HIGH externally.
3. Wait for at least 250 μs.
4. Pull the $\overline{\text{RESET}}$ pin LOW externally.
5. Perform boundary scan operations.
6. Once the boundary scan operations are completed, assert the TRST pin to enable the SWD debug mode and release the $\overline{\text{RESET}}$ pin (pull HIGH).

Remark: The JTAG interface cannot be used for debug purposes.

Table 6. Static characteristics *…continued*
T_{amb} = −40 °C to +85 °C, unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ[1]	Max	Unit
I_{OL}	LOW-level output current	V_{OL} = 0.4 V 2.0 V ≤ V_{DD} ≤ 3.6 V	4	-	-	mA
		1.8 V ≤ V_{DD} < 2.0 V	3	-	-	mA
I_{OHS}	HIGH-level short-circuit output current	V_{OH} = 0 V [14]	-	-	−45	mA
I_{OLS}	LOW-level short-circuit output current	V_{OL} = V_{DD} [14]	-	-	50	mA
I_{pd}	pull-down current	V_I = 5 V	10	50	150	μA
I_{pu}	pull-up current	V_I = 0 V; 2.0 V ≤ V_{DD} ≤ 3.6 V	−15	−50	−85	μA
		1.8 V ≤ V_{DD} < 2.0 V	−10	−50	−85	μA
		V_{DD} < V_I < 5 V	0	0	0	μA
High-drive output pin (PIO0_7)						
I_{IL}	LOW-level input current	V_I = 0 V; on-chip pull-up resistor disabled	-	0.5	10	nA
I_{IH}	HIGH-level input current	V_I = V_{DD}; on-chip pull-down resistor disabled	-	0.5	10	nA
I_{OZ}	OFF-state output current	V_O = 0 V; V_O = V_{DD}; on-chip pull-up/down resistors disabled	-	0.5	10	nA
V_I	input voltage	pin configured to provide a digital function [11][12] [13]	0	-	5.0	V
V_O	output voltage	output active	0	-	V_{DD}	V
V_{IH}	HIGH-level input voltage		0.7V_{DD}	-	-	V
V_{IL}	LOW-level input voltage		-	-	0.3V_{DD}	V
V_{hys}	hysteresis voltage		0.4	-	-	V
V_{OH}	HIGH-level output voltage	2.5 V ≤ V_{DD} ≤ 3.6 V; I_{OH} = −20 mA	V_{DD} − 0.4	-	-	V
		1.8 V ≤ V_{DD} < 2.5 V; I_{OH} = −12 mA	V_{DD} − 0.4	-	-	V
V_{OL}	LOW-level output voltage	2.0 V ≤ V_{DD} ≤ 3.6 V; I_{OL} = 4 mA	-	-	0.4	V
		1.8 V ≤ V_{DD} < 2.0 V; I_{OL} = 3 mA	-	-	0.4	V
I_{OH}	HIGH-level output current	V_{OH} = V_{DD} − 0.4 V; 2.5 V ≤ V_{DD} ≤ 3.6 V	20	-	-	mA
		1.8 V ≤ V_{DD} < 2.5 V	12	-	-	mA
I_{OL}	LOW-level output current	V_{OL} = 0.4 V 2.0 V ≤ V_{DD} ≤ 3.6 V	4	-	-	mA
		1.8 V ≤ V_{DD} < 2.0 V	3	-	-	mA
I_{OLS}	LOW-level short-circuit output current	V_{OL} = V_{DD} [14]	-	-	50	mA
I_{pd}	pull-down current	V_I = 5 V	10	50	150	μA
I_{pu}	pull-up current	V_I = 0 V 2.0 V ≤ V_{DD} ≤ 3.6 V	−15	−50	−85	μA
		1.8 V ≤ V_{DD} < 2.0 V	−10	−50	−85	μA
		V_{DD} < V_I < 5 V	0	0	0	μA

Table 7. ADC static characteristics

T_{amb} = −40 °C to +85 °C unless otherwise specified; ADC frequency 4.5 MHz, V_{DD} = 2.5 V to 3.6 V.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IA}	analog input voltage		0	-	V_{DD}	V
C_{ia}	analog input capacitance		-	-	1	pF
E_D	differential linearity error	[1][2]	-	-	±1	LSB
$E_{L(adj)}$	integral non-linearity	[3]	-	-	±1.5	LSB
E_O	offset error	[4]	-	-	±3.5	LSB
E_G	gain error	[5]	-	-	0.6	%
E_T	absolute error	[6]	-	-	±4	LSB
R_{vsi}	voltage source interface resistance		-	-	40	kΩ
R_i	input resistance	[7][8]	-	-	2.5	MΩ

[1] The ADC is monotonic, there are no missing codes.

[2] The differential linearity error (E_D) is the difference between the actual step width and the ideal step width. See Figure 7.

[3] The integral non-linearity ($E_{L(adj)}$) is the peak difference between the center of the steps of the actual and the ideal transfer curve after appropriate adjustment of gain and offset errors. See Figure 7.

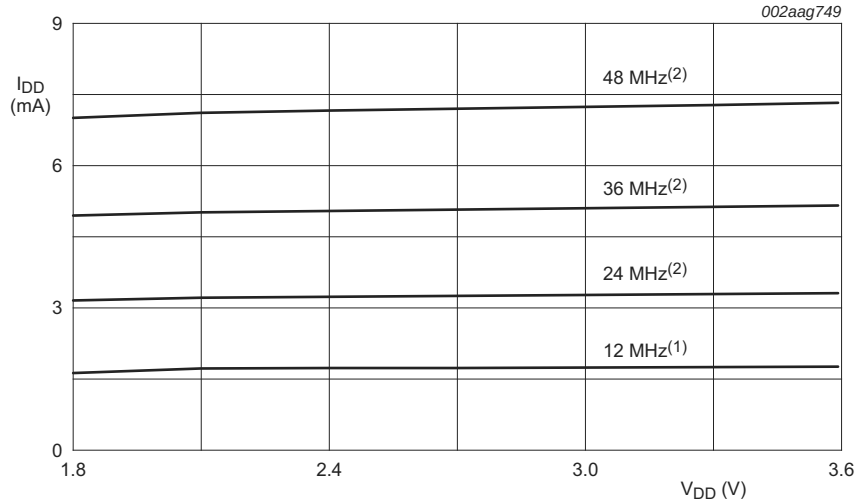
[4] The offset error (E_O) is the absolute difference between the straight line which fits the actual curve and the straight line which fits the ideal curve. See Figure 7.

[5] The gain error (E_G) is the relative difference in percent between the straight line fitting the actual transfer curve after removing offset error, and the straight line which fits the ideal transfer curve. See Figure 7.

[6] The absolute error (E_T) is the maximum difference between the center of the steps of the actual transfer curve of the non-calibrated ADC and the ideal transfer curve. See Figure 7.

[7] T_{amb} = 25 °C; maximum sampling frequency f_s = 400kSamples/s and analog input capacitance C_{ia} = 1 pF.

[8] Input resistance R_i depends on the sampling frequency fs: $R_i = 1 / (f_s \times C_{ia})$.

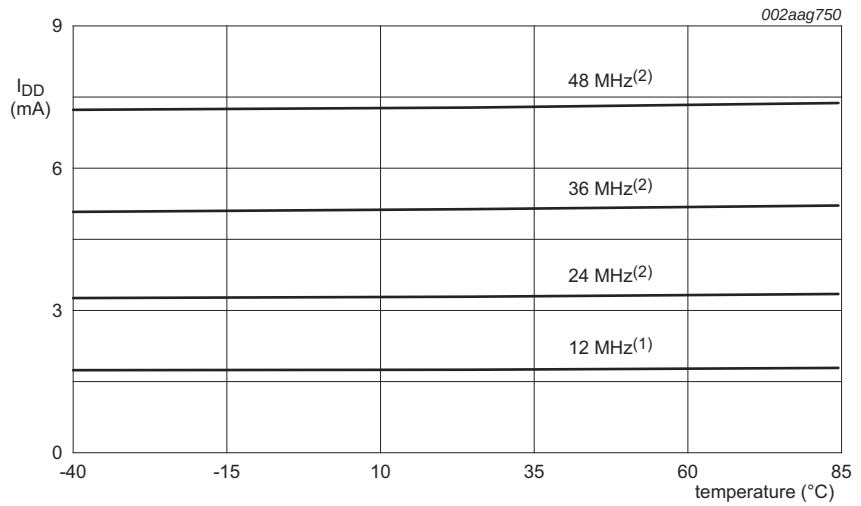


Conditions: T_{amb} = 25 °C; Active mode entered executing code `while(1){}` from flash; internal pull-up resistors disabled; BOD disabled; all peripherals disabled in the SYSAHBCLKCTRL register; all peripheral clocks disabled; low-current mode; USB_DP and USB_DM pulled LOW externally.

(1) System oscillator and system PLL disabled; IRC enabled.

(2) System oscillator and system PLL enabled; IRC disabled.

Fig 8. Typical supply current versus regulator supply voltage V_{DD} in active mode

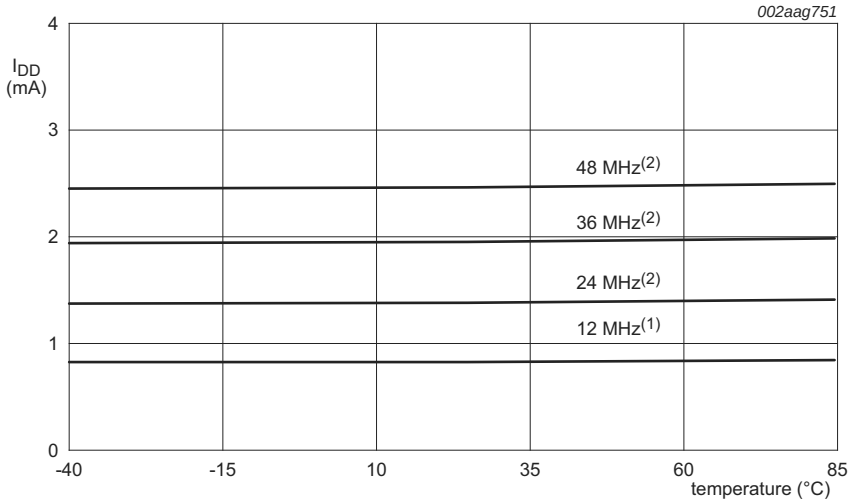


Conditions: V_{DD} = 3.3 V; Active mode entered executing code `while(1){}` from flash; internal pull-up resistors disabled; BOD disabled; all peripherals disabled in the SYSAHBCLKCTRL register; all peripheral clocks disabled; low-current mode; USB_DP and USB_DM pulled LOW externally.

(1) System oscillator and system PLL disabled; IRC enabled.

(2) System oscillator and system PLL enabled; IRC disabled.

Fig 9. Typical supply current versus temperature in Active mode

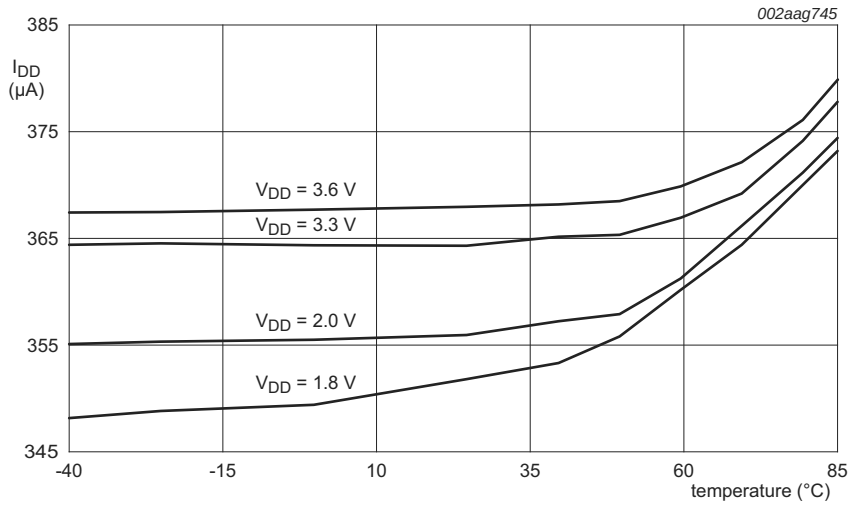


Conditions: V_{DD} = 3.3 V; Sleep mode entered from flash; internal pull-up resistors disabled; BOD disabled; all peripherals disabled in the SYSAHBCLKCTRL register; all peripheral clocks disabled; low-current mode; USB_DP and USB_DM pulled LOW externally.

(1) System oscillator and system PLL disabled; IRC enabled.

(2) System oscillator and system PLL enabled; IRC disabled.

Fig 10. Typical supply current versus temperature in Sleep mode

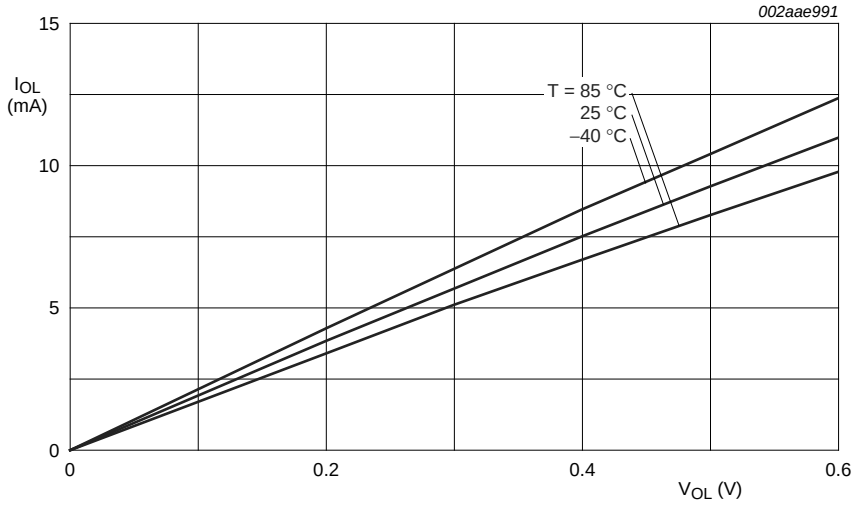


Conditions: BOD disabled; all oscillators and analog blocks turned off in the PDSLEEPCFG register; USB_DP and USB_DM pulled LOW externally.

Fig 11. Typical supply current versus temperature in Deep-sleep mode

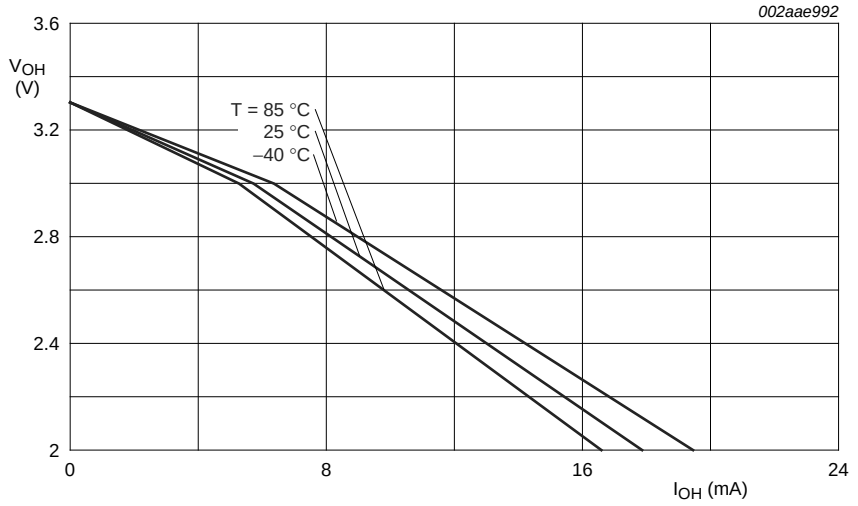
Table 9. Power consumption for individual analog and digital blocks

Peripheral	Typical supply current in mA			Notes
	n/a	12 MHz	48 MHz	
IRC	0.27	-	-	System oscillator running; PLL off; independent of main clock frequency.
System oscillator at 12 MHz	0.22	-	-	IRC running; PLL off; independent of main clock frequency.
Watchdog oscillator at 500 kHz/2	0.004	-	-	System oscillator running; PLL off; independent of main clock frequency.
BOD	0.051	-	-	Independent of main clock frequency.
Main PLL	-	0.21	-	-
ADC	-	0.08	0.29	-
CLKOUT	-	0.12	0.47	Main clock divided by 4 in the CLKOUTDIV register.
CT16B0	-	0.02	0.06	-
CT16B1	-	0.02	0.06	-
CT32B0	-	0.02	0.07	-
CT32B1	-	0.02	0.06	-
GPIO	-	0.23	0.88	GPIO pins configured as outputs and set to LOW. Direction and pin state are maintained if the GPIO is disabled in the SYSAHBCLKCFG register.
IOCONFIG	-	0.03	0.10	-
I2C	-	0.04	0.13	-
ROM	-	0.04	0.15	-
SPI0	-	0.12	0.45	-
SPI1	-	0.12	0.45	-
UART	-	0.22	0.82	-
WWDT	-	0.02	0.06	Main clock selected as clock source for the WDT.
USB	-	-	1.2	-



Conditions: V_{DD} = 3.3 V; standard port pins and PIO0_7.

Fig 16. Typical LOW-level output current I_{OL} versus LOW-level output voltage V_{OL}



Conditions: V_{DD} = 3.3 V; standard port pins.

Fig 17. Typical HIGH-level output voltage V_{OH} versus HIGH-level output source current I_{OH}

10.6 SSP interface

Table 16. Dynamic characteristics of SPI pins in SPI mode

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
SPI master (in SPI mode)							
$T_{cy(clk)}$	clock cycle time	full-duplex mode	[1]	50	-	-	ns
		when only transmitting	[1]	40			ns
t_{DS}	data set-up time	in SPI mode $2.4\ V \leq V_{DD} \leq 3.6\ V$	[2]	15	-	-	ns
		$2.0\ V \leq V_{DD} < 2.4\ V$	[2]	20			ns
		$1.8\ V \leq V_{DD} < 2.0\ V$	[2]	24	-	-	ns
t_{DH}	data hold time	in SPI mode	[2]	0	-	-	ns
$t_{v(Q)}$	data output valid time	in SPI mode	[2]	-	-	10	ns
$t_{h(Q)}$	data output hold time	in SPI mode	[2]	0	-	-	ns
SPI slave (in SPI mode)							
$T_{cy(PCLK)}$	PCLK cycle time			20	-	-	ns
t_{DS}	data set-up time	in SPI mode	[3][4]	0	-	-	ns
t_{DH}	data hold time	in SPI mode	[3][4]	$3 \times T_{cy(PCLK)} + 4$	-	-	ns
$t_{v(Q)}$	data output valid time	in SPI mode	[3][4]	-	-	$3 \times T_{cy(PCLK)} + 11$	ns
$t_{h(Q)}$	data output hold time	in SPI mode	[3][4]	-	-	$2 \times T_{cy(PCLK)} + 5$	ns

[1] $T_{cy(clk)} = (SSPCLKDIV \times (1 + SCR) \times CPSDVSR) / f_{main}$. The clock cycle time derived from the SPI bit rate $T_{cy(clk)}$ is a function of the main clock frequency f_{main}, the SPI peripheral clock divider (SSPCLKDIV), the SPI SCR parameter (specified in the SSP0CR0 register), and the SPI CPSDVSR parameter (specified in the SPI clock prescale register).

[2] $T_{amb} = -40\ °C$ to $85\ °C$.

[3] $T_{cy(clk)} = 12 \times T_{cy(PCLK)}$.

[4] $T_{amb} = 25\ °C$; for normal voltage supply range: $V_{DD} = 3.3\ V$.

For a bus-powered device, the VBUS signal does not need to be connected to the USB_VBUS pin (see Figure 27). The USB_CONNECT function can additionally be connected as shown in Figure 26 to prevent the USB from timing out when there is a significant delay between power-up and handling USB traffic.

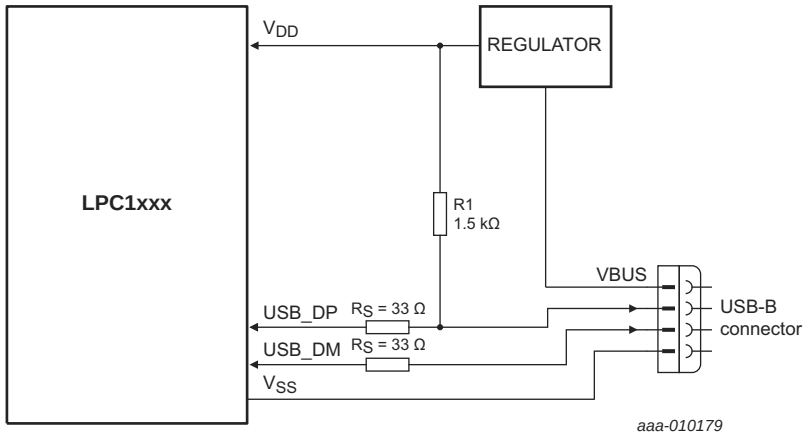


Fig 27. USB interface on a bus-powered device

Remark: When a bus-powered circuit as shown in Figure 27 is used, configure the PIO0_3/USB_VBUS pin for GPIO (PIO0_3) in the IOCON block to ensure that the USB_CONNECT signal can still be controlled by software. For details on the soft-connect feature, see the LPC11U1x *user manual* (Ref. 1).

Remark: When a self-powered circuit is used without connecting VBUS, configure the PIO0_3/USB_VBUS pin for GPIO (PIO0_3) and provide software that can detect the host presence through some other mechanism before enabling USB_CONNECT and the soft-connect feature. Enabling the soft-connect without host presence will lead to USB compliance failure.

11.2 XTAL input

The input voltage to the on-chip oscillators is limited to 1.8 V. If the oscillator is driven by a clock in slave mode, it is recommended that the input be coupled through a capacitor with C_i = 100 pF. To limit the input voltage to the specified range, choose an additional capacitor to ground C_g which attenuates the input voltage by a factor $C_i/(C_i + C_g)$. In slave mode, a minimum of 200 mV(RMS) is needed.

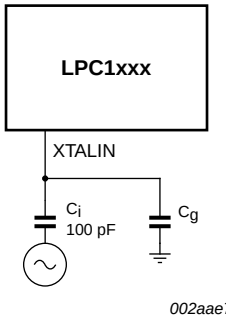


Fig 28. Slave mode operation of the on-chip oscillator

In slave mode the input clock signal should be coupled by means of a capacitor of 100 pF (Figure 28), with an amplitude between 200 mV(RMS) and 1000 mV(RMS). This corresponds to a square wave signal with a signal swing of between 280 mV and 1.4 V. The XTALOUT pin in this configuration can be left unconnected.

External components and models used in oscillation mode are shown in Figure 29 and in Table 18 and Table 19. Since the feedback resistance is integrated on chip, only a crystal and the capacitances C_{X1} and C_{X2} need to be connected externally in case of fundamental mode oscillation (the fundamental frequency is represented by L, C_L and R_S). Capacitance C_P in Figure 29 represents the parallel package capacitance and should not be larger than 7 pF. Parameters F_{OSC}, C_L, R_S and C_P are supplied by the crystal manufacturer.

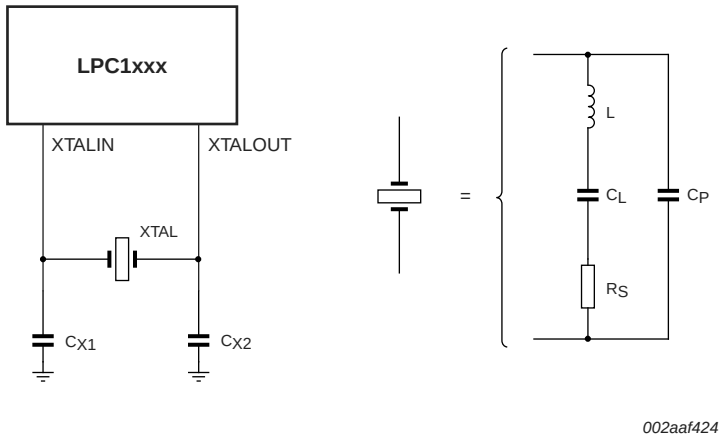
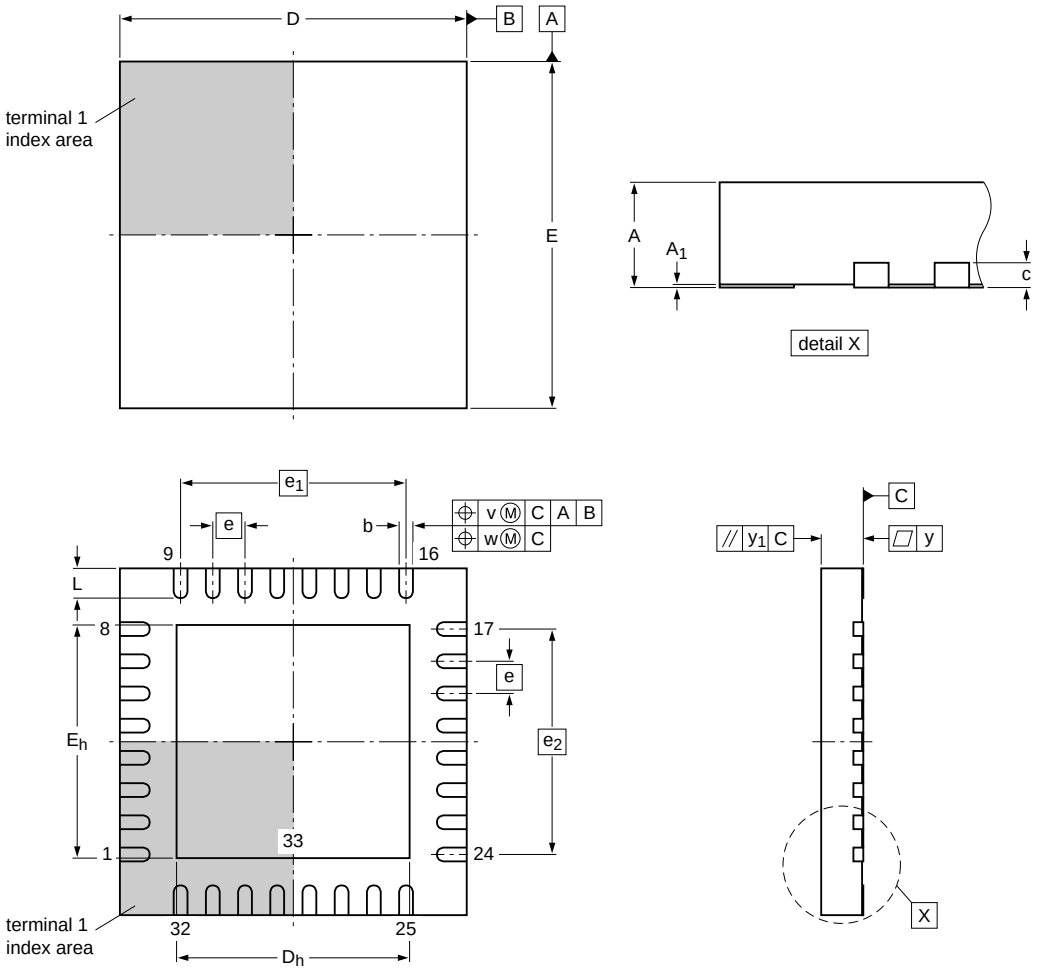


Fig 29. Oscillator modes and models: oscillation mode of operation and external crystal model used for C_{X1}/C_{X2} evaluation

12. Package outline

HVQFN33: plastic thermal enhanced very thin quad flat package; no leads; 33 terminals; body 7 x 7 x 0.85 mm



Dimensions

Unit		$A^{(1)}$	A_1	b	c	$D^{(1)}$	D_h	$E^{(1)}$	E_h	e	e_1	e_2	L	v	w	y	y_1
	max	1.00	0.05	0.35		7.1	4.85	7.1	4.85				0.75				
mm	nom	0.85	0.02	0.28	0.2	7.0	4.70	7.0	4.70	0.65	4.55	4.55	0.60	0.1	0.05	0.08	0.1
	min	0.80	0.00	0.23		6.9	4.55	6.9	4.55				0.45				

Note

1. Plastic or metal protrusions of 0.075 mm maximum per side are not included.

hvqfn33_po

Outline version	References				European projection	Issue date
	IEC	JEDEC	JEITA			
		- - -				~~09-03-17~~ 09-03-23

Fig 33. Package outline HVQFN33 (7 x 7 x 0.85 mm)

14. Abbreviations

Table 20. Abbreviations

Acronym	Description
A/D	Analog-to-Digital
ADC	Analog-to-Digital Converter
AHB	Advanced High-performance Bus
APB	Advanced Peripheral Bus
BOD	BrownOut Detection
GPIO	General Purpose Input/Output
JTAG	Joint Test Action Group
PLL	Phase-Locked Loop
RC	Resistor-Capacitor
SPI	Serial Peripheral Interface
SSI	Serial Synchronous Interface
SSP	Synchronous Serial Port
TAP	Test Access Port
USART	Universal Synchronous Asynchronous Receiver/Transmitter

15. References

[1] LPC11U1x User manual UM10462:
http://www.nxp.com/documents/user_manual/UM10462.pdf

[2] LPC11U1x Errata sheet:
http://www.nxp.com/documents/errata_sheet/ES_LPC11U1X.pdf

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from competent authorities.

Non-automotive qualified products — Unless this data sheet expressly states that this specific NXP Semiconductors product is automotive qualified, the product is not suitable for automotive use. It is neither qualified nor tested in accordance with automotive testing or application requirements. NXP Semiconductors accepts no liability for inclusion and/or use of non-automotive qualified products in automotive equipment or applications.

In the event that customer uses the product for design-in and use in automotive applications to automotive specifications and standards, customer (a) shall use the product without NXP Semiconductors' warranty of the product for such automotive applications, use and specifications, and (b) whenever customer uses the product for automotive applications beyond NXP Semiconductors' specifications such use shall be solely at customer's own risk, and (c) customer fully indemnifies NXP Semiconductors for any liability, damages or failed product claims resulting from customer design and use of the product for automotive applications beyond NXP Semiconductors' standard warranty and NXP Semiconductors' product specifications.

17.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

I²C-bus — logo is a trademark of NXP Semiconductors N.V.

18. Contact information

For more information, please visit: **http://www.nxp.com**

For sales office addresses, please send an email to: **salesaddresses@nxp.com**